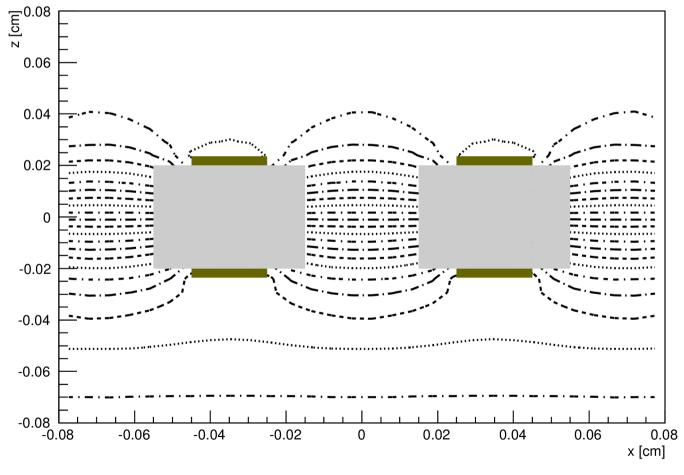
Update on Garfield++ Simulations with Open-Source Finite Element Electrostatics

Josh Renner UC Berkeley / LBNL RD51 Mini-Week, WG4 January 30, 2013

- Garfield and Garfield++ support simulations of electron/ion drift in finite-element fields
- Open-source tools Gmsh [1] and Elmer [2] can be used to create finite-element electrostatic maps
- Support now included for import of weighting field maps and use with Garfield++ signal readout methods
- See accompanying writeup and code: http://garfieldpp.web.cern.ch/garfieldpp/examples/elmer/

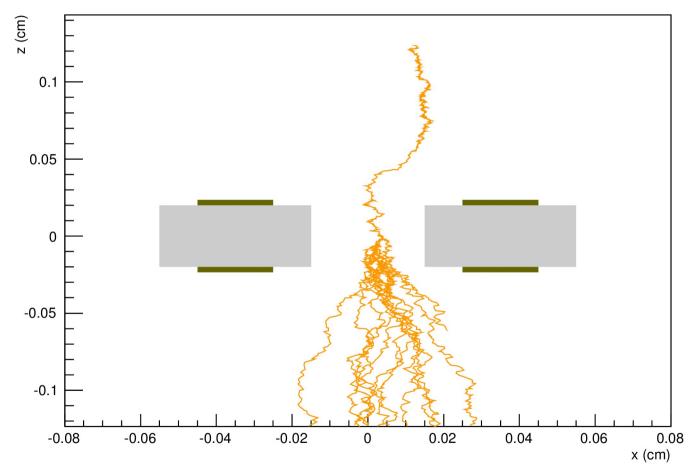
[1] Gmsh: http://geuz.org/gmsh[2] Elmer: http://www.csc.fi/english/pages/elmer

• Gmsh/Elmer + ViewFEMesh + ViewField: contours for a LEM



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• AvalancheMicroscopic + ViewFEMesh + ViewDrift: avalanche in a LEM

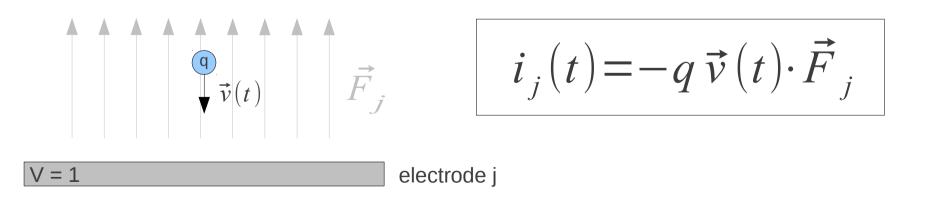


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Induced signals

- A charge moving toward an electrode induces a current; product of [1]:

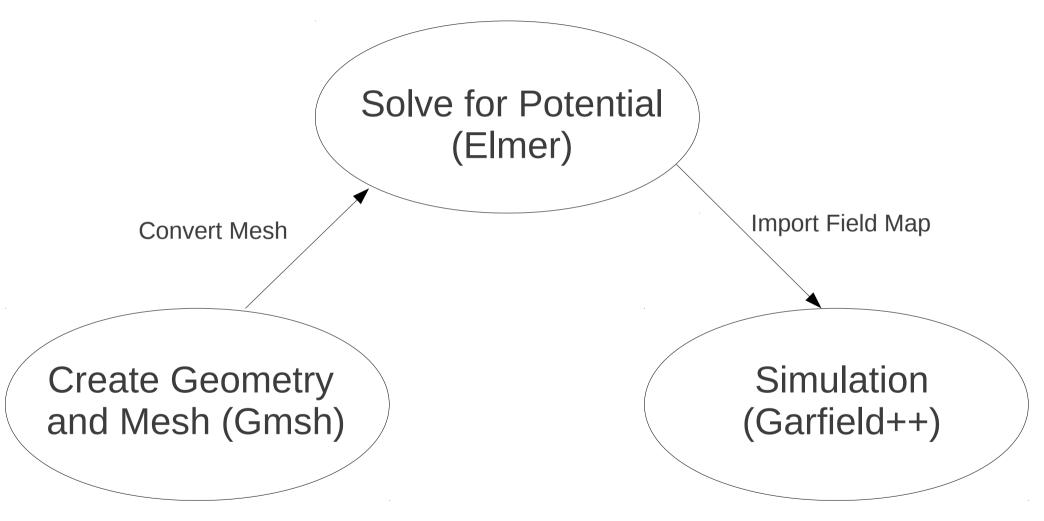
- \rightarrow the charge q
- \rightarrow the velocity of the moving charge v(t)
- → the weighting field $F = -\nabla V$, for V = 1 on electrode, V = 0 all other conductors



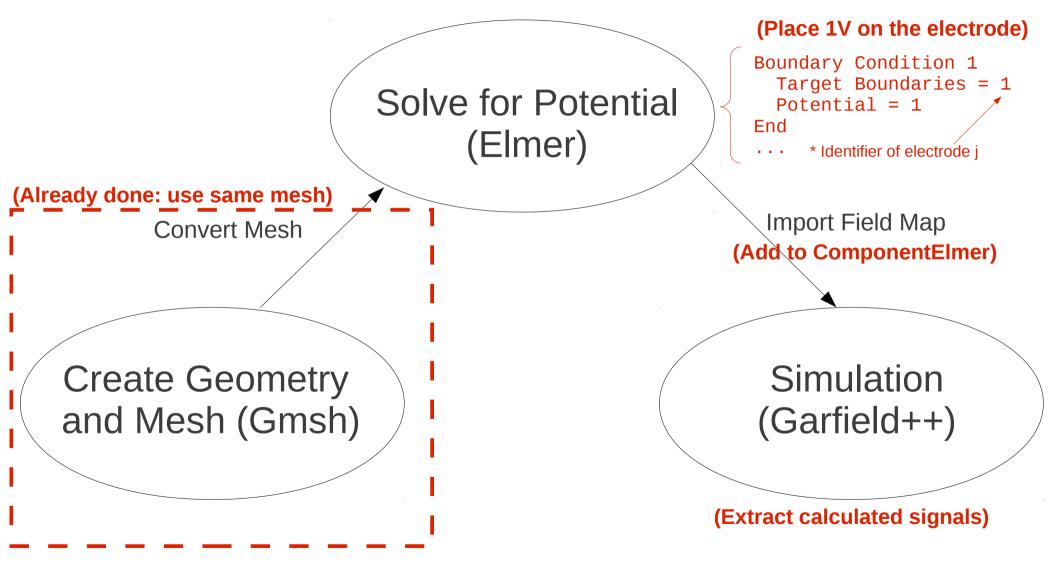
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[1] H. Spieler, "Radiation Detectors and Signal Processing," VII. Heidelberger Graduate Lectures in Physics, 2001. http://www-physics.lbl.gov/ spieler/Heidelberg Notes 2001/index.html

General finite-element drift calculation



Addition of a weighting field

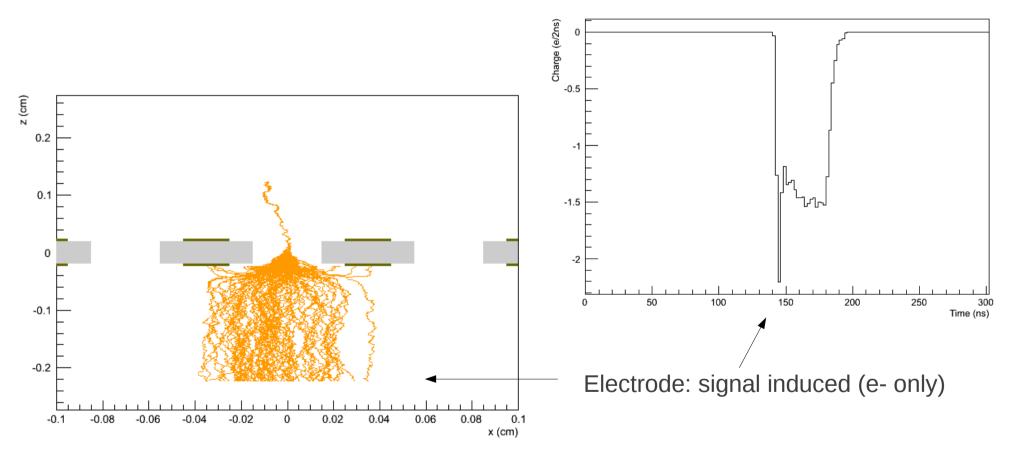


• Induced signals in Garfield++:

```
ComponentElmer * elm = new ComponentElmer(...);
                                                          Set up component;
                                                          add weighting field
elm->SetWeightingField(".result file", "wtlel");
Sensor* sensor = new Sensor();
                                                        Set up sensor to
                                                        calculate signals using
sensor->AddElectrode(elm, "wtlel");
                                                        weighting field
sensor->SetTimeWindow(tStart, binWidth, nsBins);
AvalancheMicroscopic* aval
 = new AvalancheMicroscopic();
                                        Set up avalanche to enable
                                        calculation of signals
. . .
aval->EnableSignalCalculation();
// (perform avalanche)
for(int i = 0; i < nsBins; i++) {</pre>
  double s = sensor->GetSignal("wtlel",i);
                                                           Extract the signals
  // ...
```

Example: Signal readout in a LEM

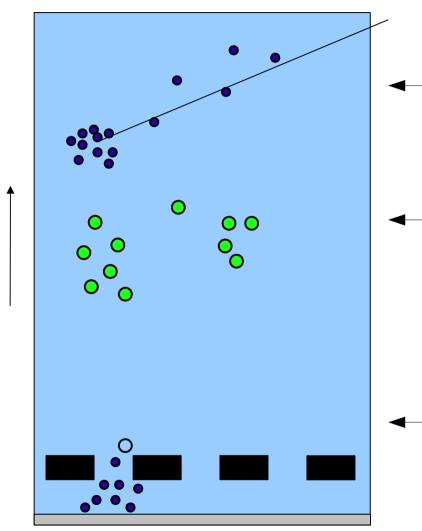
• Drift a single electron through a LEM with AvalancheMicroscopic; record induced signal



• This will be made available as an example

Example: LEM readout with attachment

• Negative ion drift*: ionization is transported as ions



Incident particle deposits energy through ionization

e- drifted until they attach to
 impurities to form negative
 ions which continue drifting

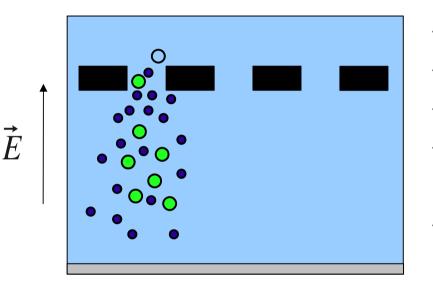
e- removed from ion and
 multiplies in the high LEM
 field yielding one detectable
 signal for each ion

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* References:

- P. Sorensen et. al. NIMA <u>686</u>, 106 (2012). arXiv:1205.6427v1. (http://dx.doi.org/10.1016/j.nima.2012.05.078)
- C. J. Martoff *et. al.* NIMA <u>440</u>, 355 (2000).
- D. Nygren. J. Phys. Conf. Series <u>65</u> (2007) 012003.

• LEM-based readout process



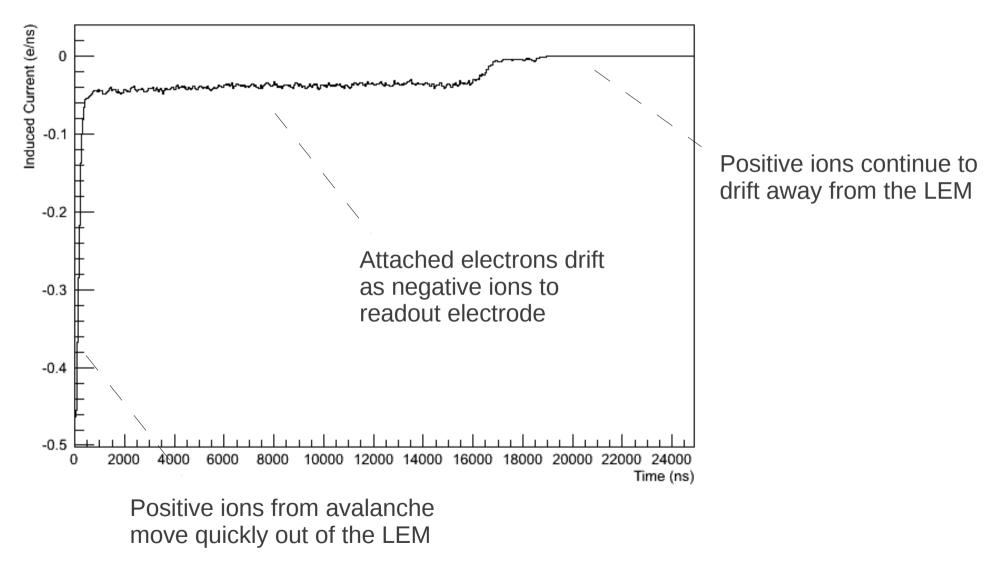
- \rightarrow e- detaches from negative ion
- \rightarrow avalanche produced
- → e- drift towards readout electrode
- → some e- attach along the way and drift as negative ions
- → meanwhile positive ions (not shown) drift back through the LEM
- Simulate in Garfield++:
 - Ar (30%) CO₂ (26%) O₂ (4%)
 - single e- incident on LEM produces an avalanche
 - drift a positive ion from each point of ionization
 - drift a negative ion from each point of e- attachment

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Collaborators: Mike Heffner and Melinda Sweany (LLNL)

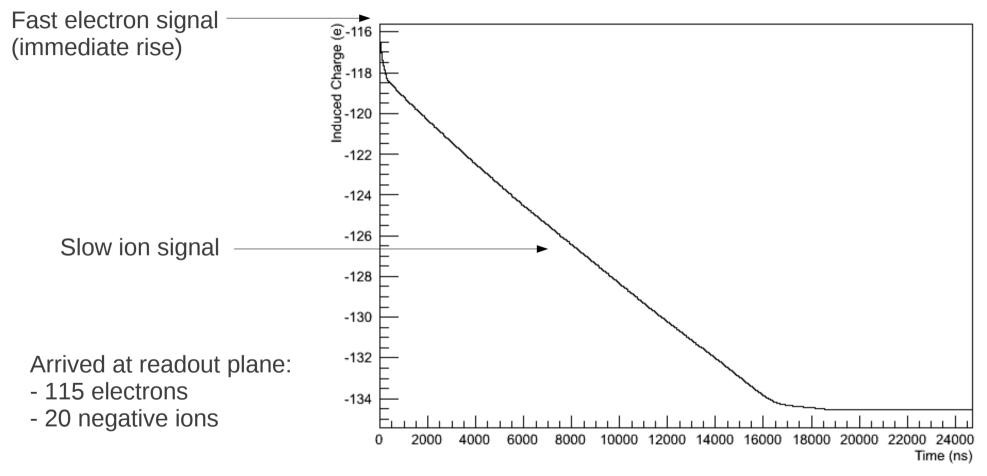
Example: LEM readout with attachment

• Ion component (+ and -) of induced signal



Example: LEM readout with attachment

• Integrated signal (all components)



• Slow (ion) component is a greater fraction of the total signal with attachment between the LEM and readout plane

• Finite element tools

- Open-source tools: Geometry (Gmsh), Electrostatics (Elmer), Simulation/visualization (Garfield++)
- Calculation of weighting fields allows simulation of induced signals on electrodes
- Updated code available now, avalanche readout example and updated LEM script for weighting field calculation to be made available
- Requests?
 - Feel free to request improvements/additions to the opensource finite element capabilities

- LLNL Negative Ion TPC Group
- Garfield++ team; especially Heinrich Schindler and Rob Veenhof
- LBNL Xenon Group and NEXT Collaboration; especially Azriel Goldschmidt and Carlos Oliveira
- DOE NNSA Stewardship Science Graduate Fellowship